

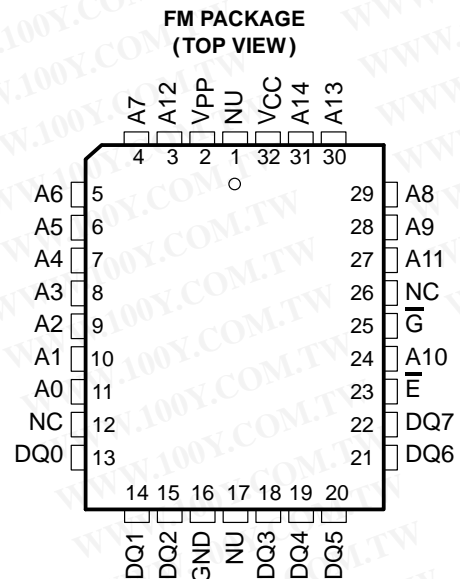
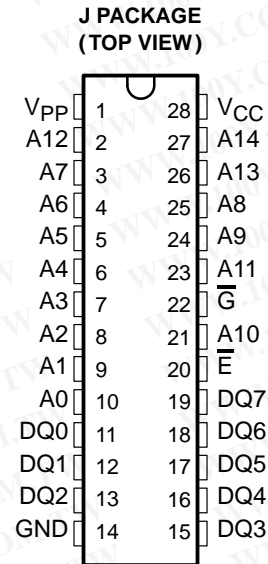
- Organization . . . 32768 by 8 Bits
- Single 5-V Power Supply
- Pin Compatible With Existing 256K MOS ROMs, PROMs, and EPROMs
- All Inputs/Outputs Fully TTL Compatible
- Max Access/Min Cycle Time  
 $V_{CC} \pm 10\%$ 

'27C/PC256-10	100 ns
'27C/PC256-12	120 ns
'27C/PC256-15	150 ns
'27C/PC256-17	170 ns
'27C/PC256-20	200 ns
'27C/PC256-25	250 ns
- Power Saving CMOS Technology
- Very High-Speed SNAP! Pulse Programming
- 3-State Output Buffers
- 400-mV Minimum DC Noise Immunity With Standard TTL Loads
- Latchup Immunity of 250 mA on All Input and Output Lines
- Low Power Dissipation ( $V_{CC} = 5.5 V$ )
  - Active . . . 165 mW Worst Case
  - Standby . . . 1.4 mW Worst Case (CMOS Input Levels)
- Temperature Range Options
- 256K EPROM Available With MIL-STD-883C Class B High Reliability Processing (SMJ27C256)

### description

The TMS27C256 series are 32768 by 8-bit (262144-bit), ultraviolet (UV) light erasable, electrically programmable read-only memories (EPROMs).

The TMS27PC256 series are 32768 by 8-bit (262144-bit), one-time programmable (OTP) electrically programmable read-only memories (PROMs).



PIN NOMENCLATURE	
A0-A14	Address Inputs
DQ0-DQ7	Inputs (programming)/Outputs
E	Chip Enable/Powerdown
G	Output Enable
GND	Ground
NC	No Internal Connection
NU	Make No External Connection
VCC	5-V Power Supply
VPP	13-V Power Supply †

† Only in program mode



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

**TMS27C256 32768 BY 8-BIT UV ERASABLE  
TMS27PC256 32768 BY 8-BIT  
PROGRAMMABLE READ-ONLY MEMORIES**

SMLS256H- SEPTEMBER 1984 - REVISED NOVEMBER 1997

勝特力材料 886-3-5753170  
勝特力电子(上海) 86-21-54151736  
勝特力电子(深圳) 86-755-83298787  
[Http://www.100y.com.tw](http://www.100y.com.tw)

**description (continued)**

These devices are fabricated using power-saving CMOS technology for high speed and simple interface with MOS and bipolar circuits. All inputs (including program data inputs) can be driven by Series 74 TTL circuits without the use of external pull-up resistors. Each output can drive one Series 74 TTL circuit without external resistors.

The data outputs are 3-state for connecting multiple devices to a common bus. The TMS27C256 and the TMS27PC256 are pin compatible with 28-pin 256K MOS ROMs, PROMs, and EPROMs.

The TMS27C256 EPROM is offered in a dual-in-line ceramic package (J suffix) designed for insertion in mounting-hole rows on 15,2-mm (600-mil) centers. The TMS27PC256 OTP PROM is supplied in a 32-lead plastic leaded chip-carrier package using 1,25-mm (50-mil) lead spacing (FM suffix).

The TMS27C256 and TMS27PC256 are offered with two choices of temperature ranges of 0°C to 70°C (JL and FML suffixes) and - 40°C to 85°C (JE and FME suffixes). See Table 1.

All package styles conform to JEDEC standards.

**Table 1. Temperature Range Suffixes**

EPROM AND OTP PROM	SUFFIX FOR OPERATING FREE-AIR TEMPERATURE RANGES	
	0°C TO 70°C	- 40°C TO 85°C
TMS27C512-xxx	JL	JE
TMS27PC512-xxx	FML	FME

These EPROMs and OTP PROMs operate from a single 5-V supply (in the read mode), thus are ideal for use in microprocessor-based systems. One other 13-V supply is needed for programming. All programming signals are TTL level. These devices are programmable by the SNAP! Pulse programming algorithm. The SNAP! Pulse programming algorithm uses a  $V_{PP}$  of 13 V and a  $V_{CC}$  of 6.5 V for a nominal programming time of four seconds. For programming outside the system, existing EPROM programmers can be used. Locations can be programmed singly, in blocks, or at random.

## operation

The seven modes of operation are listed in Table 2. The read mode requires a single 5-V supply. All inputs are TTL level except for  $V_{PP}$  during programming (13 V for SNAP! Pulse), and 12 V on A9 for the signature mode.

**Table 2. Operation Modes**

FUNCTION	MODE†							
	READ	OUTPUT DISABLE	STANDBY	PROGRAMMING	VERIFY	PROGRAM INHIBIT	SIGNATURE MODE	
$\bar{E}$	$V_{IL}$	$V_{IL}$	$V_{IH}$	$V_{IL}$	$V_{IH}$	$V_{IH}$	$V_{IL}$	
$\bar{G}$	$V_{IL}$	$V_{IH}$	X	$V_{IH}$	$V_{IL}$	X	$V_{IL}$	
$V_{PP}$	$V_{CC}$	$V_{CC}$	$V_{CC}$	$V_{PP}$	$V_{PP}$	$V_{PP}$	$V_{CC}$	
$V_{CC}$	$V_{CC}$	$V_{CC}$	$V_{CC}$	$V_{CC}$	$V_{CC}$	$V_{CC}$	$V_{CC}$	
A9	X	X	X	X	X	X	$V_{H}‡$   $V_{H}‡$	
A0	X	X	X	X	X	X	$V_{IL}$   $V_{IH}$	
DQ0–DQ7	Data Out	Hi-Z	Hi-Z	Data In	Data Out	Hi-Z	CODE	
							MFG	DEVICE
							97	04

† X can be  $V_{IL}$  or  $V_{IH}$ .

‡  $V_{H} = 12 V \pm 0.5 V$ .

## read/output disable

When the outputs of two or more TMS27C256s or TMS27PC256s are connected in parallel on the same bus, the output of any particular device in the circuit can be read with no interference from the competing outputs of the other devices. To read the output of a single device, a low-level signal is applied to the  $\bar{E}$  and  $\bar{G}$  pins. All other devices in the circuit should have their outputs disabled by applying a high-level signal to one of these pins. Output data is accessed at pins DQ0 through DQ7.

## latchup immunity

Latchup immunity on the TMS27C256 and TMS27PC256 is a minimum of 250 mA on all inputs and outputs. This feature provides latchup immunity beyond any potential transients at the P.C. board level when the devices are interfaced to industry-standard TTL or MOS logic devices. Input-output layout approach controls latchup without compromising performance or packing density.

## power down

Active  $I_{CC}$  supply current can be reduced from 30 mA to 500  $\mu A$  (TTL-level inputs) or 250  $\mu A$  (CMOS-level inputs) by applying a high TTL or CMOS signal to the  $\bar{E}$  pin. In this mode all outputs are in the high-impedance state.

## erasure (TMS27C256)

Before programming, the TMS27C256 EPROM is erased by exposing the chip through the transparent lid to a high intensity ultraviolet light (wavelength 2537 Å). EPROM erasure before programming is necessary to assure that all bits are in the logic high state. Logic lows are programmed into the desired locations. A programmed logic low can be erased only by ultraviolet light. The recommended minimum exposure dose (UV intensity  $\times$  exposure time) is 15-W•s/cm<sup>2</sup>. A typical 12-mW/cm<sup>2</sup>, filterless UV lamp erases the device in 21 minutes. The lamp should be located about 2.5 cm above the chip during erasure. It should be noted that normal ambient light contains the correct wavelength for erasure. Therefore, when using the TMS27C256, the window should be covered with an opaque label.

**TMS27C256 32768 BY 8-BIT UV ERASABLE  
TMS27PC256 32768 BY 8-BIT  
PROGRAMMABLE READ-ONLY MEMORIES**

SMLS256H— SEPTEMBER 1984 — REVISED NOVEMBER 1997

勝特力材料 886-3-5753170  
勝特力电子(上海) 86-21-54151736  
勝特力电子(深圳) 86-755-83298787  
[Http://www.100y.com.tw](http://www.100y.com.tw)

**initializing (TMS27PC256)**

The one-time programmable TMS27PC256 PROM is provided with all bits in the logic high state, then logic lows are programmed into the desired locations. Logic lows programmed into an OTP PROM cannot be erased.

**SNAP! Pulse programming**

The 256K EPROM and OTP PROM are programmed using the TI SNAP! Pulse programming algorithm illustrated by the flowchart in Figure 1, which programs in a nominal time of four seconds. Actual programming time varies as a function of the programmer used.

Data is presented in parallel (eight bits) on pins DQ0 to DQ7. Once addresses and data are stable,  $\bar{E}$  is pulsed.

The SNAP! Pulse programming algorithm uses initial pulses of 100 microseconds ( $\mu$ s) followed by a byte verification to determine when the addressed byte has been successfully programmed. Up to 10 (ten) 100- $\mu$ s pulses per byte are provided before a failure is recognized.

The programming mode is achieved when  $V_{PP} = 13$  V,  $V_{CC} = 6.5$  V,  $\bar{G} = V_{IH}$ , and  $\bar{E} = V_{IL}$ . More than one device can be programmed when the devices are connected in parallel. Locations can be programmed in any order. When the SNAP! Pulse programming routine is complete, all bits are verified with  $V_{CC} = V_{PP} = 5$  V.

**program inhibit**

Programming can be inhibited by maintaining a high level input on the  $\bar{E}$  pin.

**program verify**

Programmed bits can be verified with  $V_{PP} = 13$  V when  $\bar{G} = V_{IL}$  and  $\bar{E} = V_{IH}$ .

**signature mode**

The signature mode provides access to a binary code identifying the manufacturer and type. This mode is activated when A9 is forced to 12 V. Two identifier bytes are accessed by toggling A0. All other addresses must be held low. The signature code for these devices is 9704. A0 selects the manufacturer's code 97 (Hex), and A0 high selects the device code 04, as shown in Table 3.

**Table 3. Signature Mode**

IDENTIFIER†	PINS									
	A0	DQ7	DQ6	DQ5	DQ4	DQ3	DQ2	DQ1	DQ0	HEX
MANUFACTURER CODE	$V_{IL}$	1	0	0	1	0	1	1	1	97
DEVICE CODE	$V_{IH}$	0	0	0	0	0	1	0	0	04

†  $\bar{E} = \bar{G} = V_{IL}$ , A9 =  $V_{IH}$ , A1–A8 =  $V_{IL}$ , A10–A15 =  $V_{IL}$ ,  $V_{PP} = V_{CC}$ ,  $\overline{PGM} = V_{IH}$  or  $V_{IL}$ .



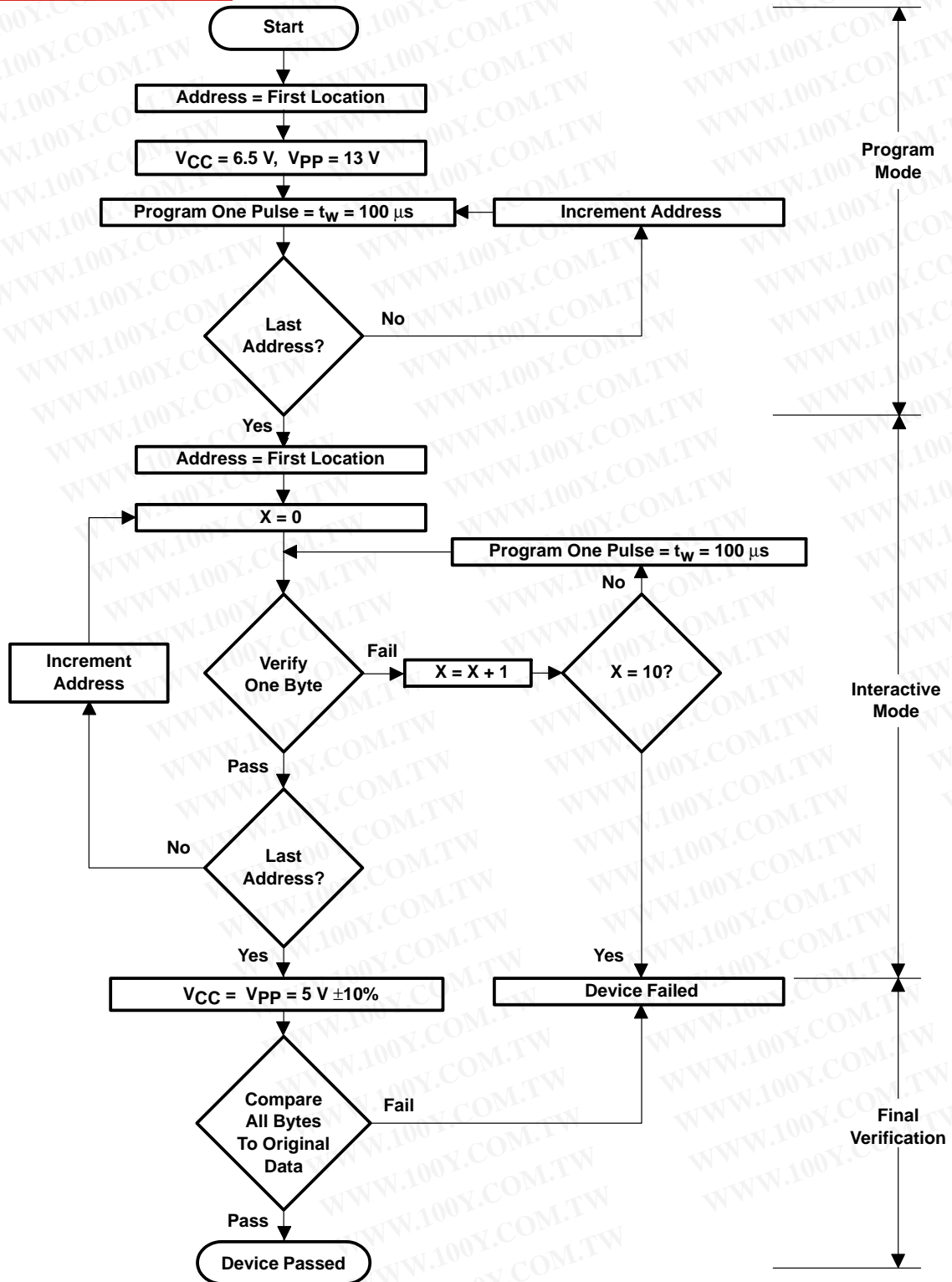


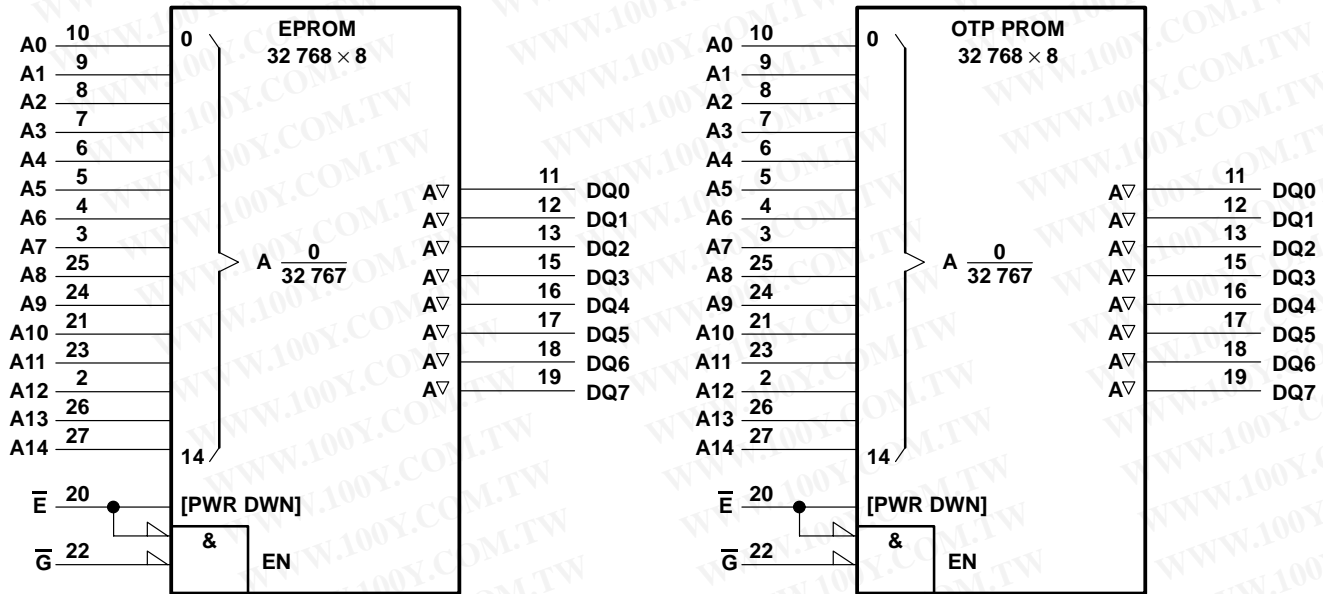
Figure 1. SNAP! Pulse Programming Flowchart

**TMS27C256 32768 BY 8-BIT UV ERASABLE  
TMS27PC256 32768 BY 8-BIT  
PROGRAMMABLE READ-ONLY MEMORIES**

SMLS256H- SEPTEMBER 1984 - REVISED NOVEMBER 1997

勝特力材料 886-3-5753170  
勝特力电子(上海) 86-21-54151736  
勝特力电子(深圳) 86-755-83298787  
Http://www.100y.com.tw

**logic symbol†**



† These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for J package.

**absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡**

- Supply voltage range,  $V_{CC}$  (see Note 1) : ..... -0.6 V to 7 V
- Supply voltage range,  $V_{PP}$  : ..... -0.6 V to 14 V
- Input voltage range (see Note 1): All inputs except A9 : ..... -0.6 V to  $V_{CC} + 1$  V
- A9 : ..... -0.6 V to 13.5 V
- Output voltage range (see Note 1) : ..... -0.6 V to  $V_{CC} + 1$  V
- Operating free-air temperature range ('27C256-\_\_JL, '27PC256-\_\_FML)  $T_A$  : ..... 0°C to 70°C
- Operating free-air temperature range ('27C5256-\_\_JE, '27PC256-\_\_FME)  $T_A$  : ..... -40°C to 85°C
- Storage temperature range,  $T_{stg}$  : ..... -65°C to 150°C

‡ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to GND.



**recommended operating conditions**

		MIN	NOM	MAX	UNIT	
V <sub>CC</sub>	Supply voltage	Read mode (see Note 2)	4.5	5	5.5	V
		SNAP! Pulse programming algorithm	6.25	6.5	6.75	
V <sub>PP</sub>	Supply voltage	Read mode	V <sub>CC</sub> -0.6		V <sub>CC</sub> +0.6	V
		SNAP! Pulse programming algorithm	12.75	13	13.25	
V <sub>IH</sub>	High-level dc input voltage	TTL	2		V <sub>CC</sub> +1	V
		CMOS	V <sub>CC</sub> -0.2		V <sub>CC</sub> +1	
V <sub>IL</sub>	Low-level dc input voltage	TTL	-0.5		0.8	V
		CMOS	-0.5		0.2	
T <sub>A</sub>	Operating free-air temperature	'27C256-__JL '27PC256-__FML		0	70	°C
T <sub>A</sub>	Operating free-air temperature	'27C256-__JE '27PC256-__FME		-40	85	°C

NOTE 2: V<sub>CC</sub> must be applied before or at the same time as V<sub>PP</sub> and removed after or at the same time as V<sub>PP</sub>. The device must not be inserted into or removed from the board when V<sub>PP</sub> or V<sub>CC</sub> is applied.

**electrical characteristics over recommended ranges of operating conditions**

PARAMETER		TEST CONDITIONS	MIN	TYP†	MAX	UNIT	
V <sub>OH</sub>	High-level dc output voltage	I <sub>OH</sub> = -2.5 mA	3.5			V	
		I <sub>OH</sub> = -20 μA	V <sub>CC</sub> - 0.1				
V <sub>OL</sub>	Low-level dc output voltage	I <sub>OL</sub> = 2.1 mA	0.4			V	
		I <sub>OL</sub> = 20 μA	0.1				
I <sub>I</sub>	Input current (leakage)	V <sub>I</sub> = 0 V to 5.5 V	±1			μA	
I <sub>O</sub>	Output current (leakage)	V <sub>O</sub> = 0 V to V <sub>CC</sub>	±1			μA	
I <sub>PP1</sub>	V <sub>PP</sub> supply current	V <sub>PP</sub> = V <sub>CC</sub> = 5.5 V	1			10	μA
I <sub>PP2</sub>	V <sub>PP</sub> supply current (during program pulse)	V <sub>PP</sub> = 13 V	35			50	mA
I <sub>CC1</sub>	V <sub>CC</sub> supply current (standby)	TTL-input level	V <sub>CC</sub> = 5.5 V, $\bar{E} = V_{IH}$		250	500	μA
		CMOS-input level	V <sub>CC</sub> = 5.5 V, $\bar{E} = V_{CC}$		100	250	
I <sub>CC2</sub>	V <sub>CC</sub> supply current (active)	V <sub>CC</sub> = 5.5 V, $\bar{E} = V_{IL}$ , t <sub>cycle</sub> = minimum cycle time, outputs open			15	30	mA

**capacitance over recommended ranges of supply voltage and operating free-air temperature, f = 1 MHz†**

PARAMETER		TEST CONDITIONS	MIN	TYP‡	MAX	UNIT
C <sub>i</sub>	Input capacitance	V <sub>I</sub> = 0, f = 1 MHz	6		10	pF
C <sub>o</sub>	Output capacitance	V <sub>O</sub> = 0, f = 1 MHz	10		14	pF

† Capacitance measurements are made on a sample basis only.

‡ Typical values are at T<sub>A</sub> = 25°C and nominal voltages.

**TMS27C256 32768 BY 8-BIT UV ERASABLE  
TMS27PC256 32768 BY 8-BIT  
PROGRAMMABLE READ-ONLY MEMORIES**

SMLS256H- SEPTEMBER 1984 - REVISED NOVEMBER 1997

勝特力材料 886-3-5753170  
勝特力电子(上海) 86-21-54151736  
勝特力电子(深圳) 86-755-83298787  
Http://www.100y.com.tw

**switching characteristics over recommended range of operating conditions**

PARAMETER	TEST CONDITIONS (SEE NOTES 3 AND 4)	'27C256-10 '27PC256-10		'27C256-12 '27PC256-12		'27C256-15 '27PC256-15		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
$t_{a(A)}$ Access time from address	$C_L = 100$ pF, 1 Series 74 TTL Load, Input $t_r \leq 20$ ns, Input $t_f \leq 20$ ns	100		120		150		ns
$t_{a(E)}$ Access time from chip enable		100		120		150		ns
$t_{en(G)}$ Output enable time from $\overline{G}$		55		55		75		ns
$t_{dis}$ Output disable time from $\overline{G}$ or $\overline{E}$ , whichever occurs first†		0	45	0	45	0	60	ns
$t_{v(A)}$ Output data valid time after change of address, $\overline{E}$ , or $\overline{G}$ , whichever occurs first†		0		0		0		ns

PARAMETER	TEST CONDITIONS (SEE NOTES 3 AND 4)	'27C256-17 '27PC256-17		'27C256-20 '27PC256-20		'27C256-25 '27PC256-25		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
$t_{a(A)}$ Access time from address	$C_L = 100$ pF, 1 Series 74 TTL Load, Input $t_r \leq 20$ ns, Input $t_f \leq 20$ ns	170		200		250		ns
$t_{a(E)}$ Access time from chip enable		170		200		250		ns
$t_{en(G)}$ Output enable time from $\overline{G}$		75		75		100		ns
$t_{dis}$ Output disable time from $\overline{G}$ or $\overline{E}$ , whichever occurs first†		0	60	0	60	0	60	ns
$t_{v(A)}$ Output data valid time after change of address, $\overline{E}$ , or $\overline{G}$ , whichever occurs first†		0		0		0		ns

† Value calculated from 0.5 V delta to measured level. This parameter is only sampled and not 100% tested.

NOTES: 3. For all switching characteristics the input pulse levels are 0.4 V to 2.4 V. Timing measurements are made at 2 V for logic high and 0.8 V for logic low) (see Figure 2).

4. Common test conditions apply for the  $t_{dis}$  except during programming.

**switching characteristics for programming:  $V_{CC} = 6.50$  V and  $V_{PP} = 13$  V (SNAP! Pulse),  $T_A = 25^\circ$  C (see Note 3)**

PARAMETER	MIN	MAX	UNIT
$t_{dis(G)}$ Output disable time from $\overline{G}$	0	130	ns
$t_{en(G)}$ Output enable time from $\overline{G}$		150	ns

NOTE 3: For all switching characteristics, the input pulse levels are 0.4 V to 2.4 V. Timing measurements are made at 2 V for logic high and 0.8 V for logic low).

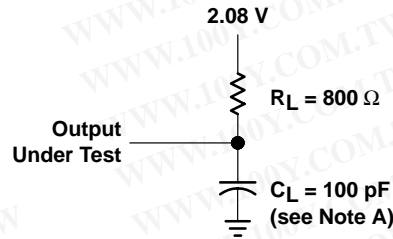
**timing requirements for programming**

	MIN	NOM	MAX	UNIT
$t_{h(A)}$ Hold time, address	0			$\mu$ s
$t_{h(D)}$ Hold time, data	2			$\mu$ s
$t_{w(IPGM)}$ Pulse duration, initial program	95	100	105	$\mu$ s
$t_{su(A)}$ Setup time, address	2			$\mu$ s
$t_{su(G)}$ Setup time, $\overline{G}$	2			$\mu$ s
$t_{su(E)}$ Setup time, $\overline{E}$	2			$\mu$ s
$t_{su(D)}$ Setup time, data	2			$\mu$ s
$t_{su(VPP)}$ Setup time, $V_{PP}$	2			$\mu$ s
$t_{su(VCC)}$ Setup time, $V_{CC}$	2			$\mu$ s





**PARAMETER MEASUREMENT INFORMATION**



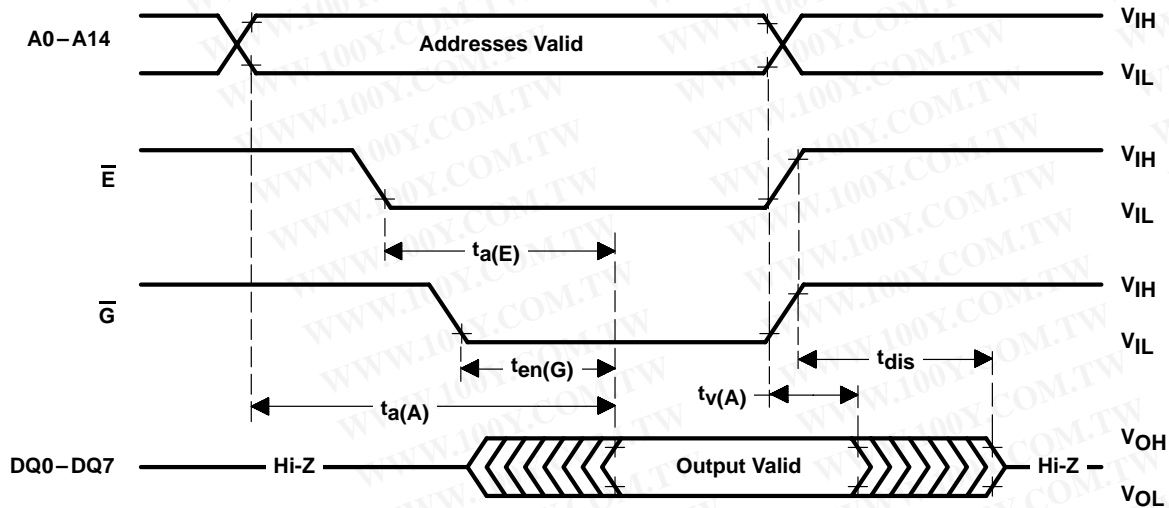
NOTE A:  $C_L$  includes probe and fixture capacitance.

**ac testing input/output wave forms**



AC testing inputs are driven at 2.4 V for logic high and 0.4 V for logic low. Timing measurements are made at 2 V for logic high and 0.8 V for logic low for both inputs and outputs.

**Figure 2. AC Testing Output Load Circuit**



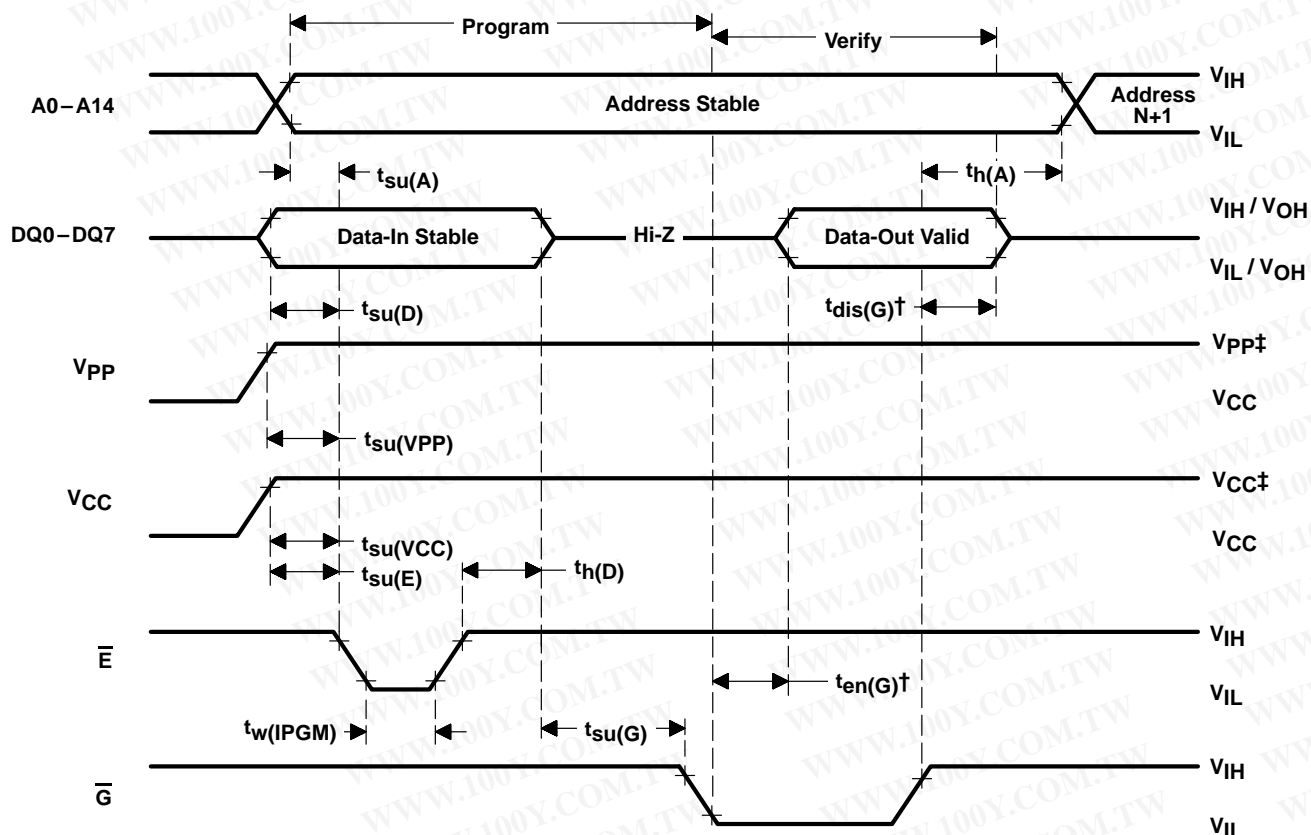
**Figure 3. Read-Cycle Timing**

**TMS27C256 32768 BY 8-BIT UV ERASABLE  
TMS27PC256 32768 BY 8-BIT  
PROGRAMMABLE READ-ONLY MEMORIES**

SMLS256H- SEPTEMBER 1984 - REVISED NOVEMBER 1997

勝特力材料 886-3-5753170  
勝特力电子(上海) 86-21-54151736  
勝特力电子(深圳) 86-755-83298787  
Http://www.100y.com.tw

**PARAMETER MEASUREMENT INFORMATION**



†  $t_{dis}(G)$  and  $t_{en}(G)$  are characteristics of the device but must be accommodated by the programmer

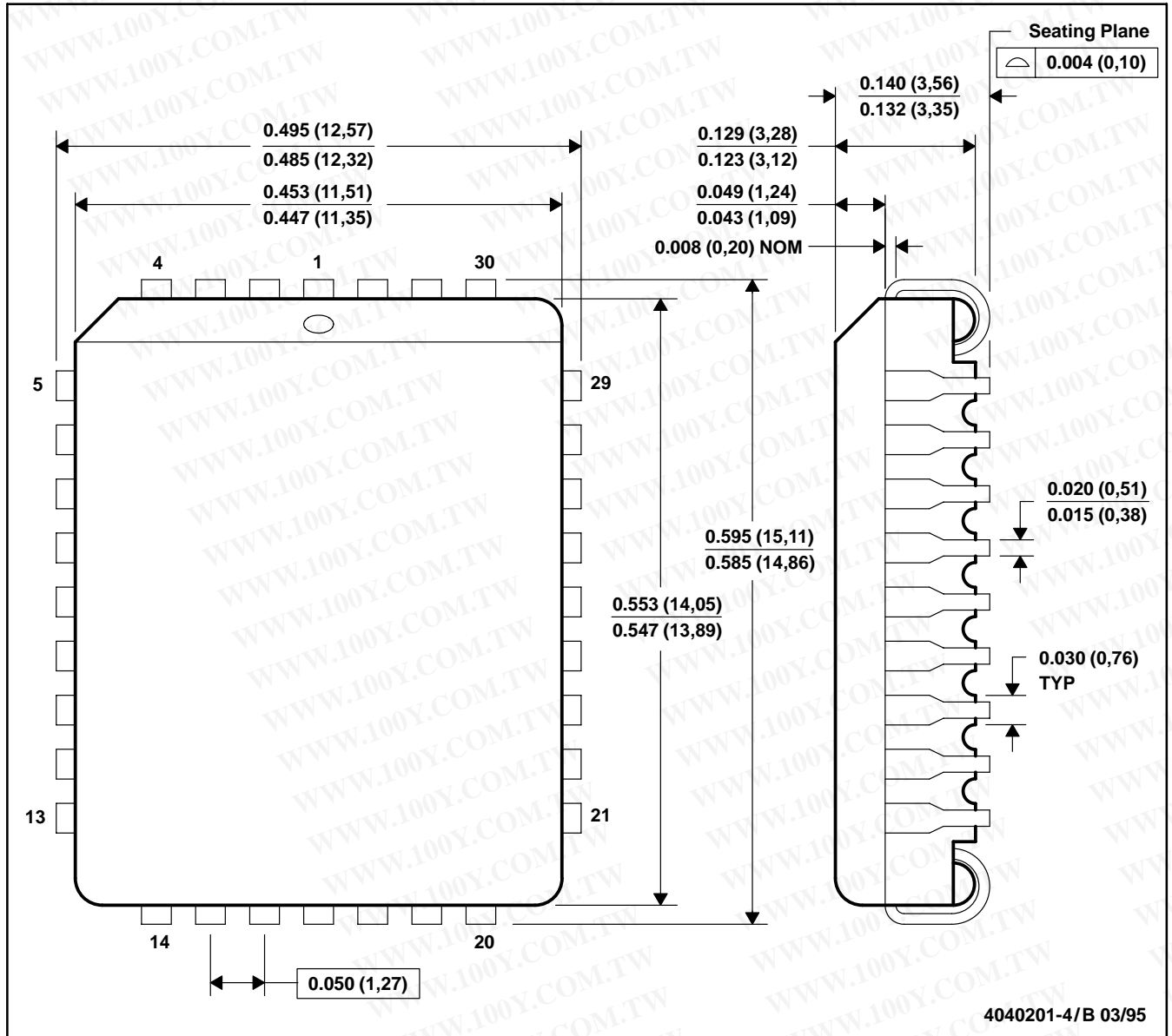
‡ 13-V  $V_{PP}$  and 6.5-V  $V_{CC}$  for SNAP! Pulse programming

**Figure 4. Program-Cycle Timing (SNAP! Pulse Programming)**



FM (R-PQCC-J32)

PLASTIC J-LEADED CHIP CARRIER



- NOTES: A. All linear dimensions are in inches (millimeters).  
 B. This drawing is subject to change without notice.  
 C. Falls within JEDEC MS-016

**TMS27C256 32768 BY 8-BIT UV ERASABLE  
TMS27PC256 32768 BY 8-BIT  
PROGRAMMABLE READ-ONLY MEMORIES**

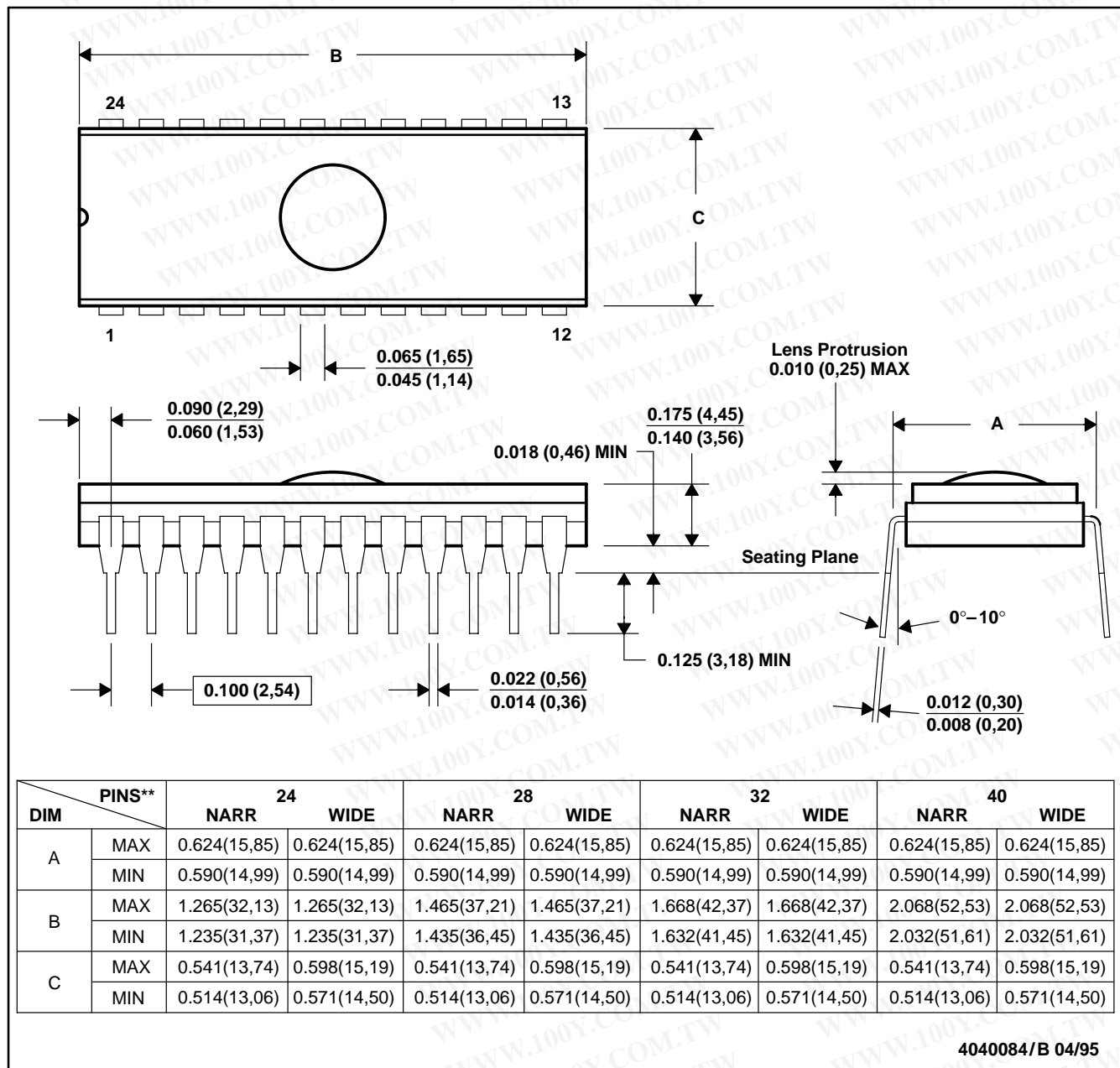
SMLS256H- SEPTEMBER 1984 - REVISED NOVEMBER 1997

勝特力材料 886-3-5753170  
勝特力电子(上海) 86-21-54151736  
勝特力电子(深圳) 86-755-83298787  
[Http://www.100y.com.tw](http://www.100y.com.tw)

**J (R-CDIP-T\*\*)**

**CERAMIC SIDE-BRAZE DUAL-IN-LINE PACKAGE**

24 PIN SHOWN



- NOTES: A. All linear dimensions are in inches (millimeters).  
 B. This drawing is subject to change without notice.  
 C. This package can be hermetically sealed with a ceramic lid using glass frit.  
 D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.

勝特力材料 886-3-5753170  
勝特力电子(上海) 86-21-54151736  
勝特力电子(深圳) 86-755-83298787  
[Http://www.100y.com.tw](http://www.100y.com.tw)

#### IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

Copyright © 1997, Texas Instruments Incorporated